

**Patent Claims**

1. (Once amended) A method of testing the ESD performance of an IC device, comprising  
probing the device with a laser beam,  
monitoring the amount of light reflected from the device, and  
comparing the amount of light reflected to the amount of light reflected from an  
I/O cell having good ESD performance.
8. (Once amended) A method of Claim 5, wherein several samples are taken of each probed  
location, at the same I/O signal voltage level, and the results averaged.